Search Notes

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Application/Control No.	Applicant(s)/Patent under Reexamination
09/853,770	SHIGEMATSU ET AL.
Examiner	Art Unit
Ellen C. Tran	2134

SEARCHED					
Class	Subclass	Date	Examiner		
713	186	3/4/2006	ECT		
713	186	10/22/2006	ECT		
726	9 .	10/22/2006	ECT		
726	20	10/22/2006	ECT		

INTERFERENCE SEARCHED					
Class	Subclass	Date	Examiner		
	L				

SEARCH NOTES (INCLUDING SEARCH STRATEGY)			
	DATE	EXMR	
USPTO, USPG, EPO, JO, DERWENT, IBM TECH DES, INVENTOR - PALM	3/4/2006	ECT	
USPTO, USPG, EPO, JPO, DERWENT, IBM TECH DES	10/22/2006	ECT	
NPL - IEEE XPLORE	10/22/2006	ECT	
All claims have been reviewed by Examiner for possible 101 rejections	10/22/2006	ECT	